TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74VHC273F,TC74VHC273FT,TC74VHC273FK

Octal D-Type Flip-Flop with Clear

The TC74VHC273 is an advanced high speed CMOS OCTAL D-TYPE FLIP FLOP fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

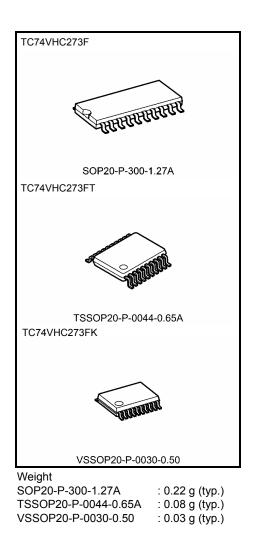
Information signals applied to D inputs are transferred to the Q outputs on the positive going edge of the clock pulse.

When the $\overline{\text{CLR}}$ input is held "L", the Q outputs are at a low logic level independent of the other inputs.

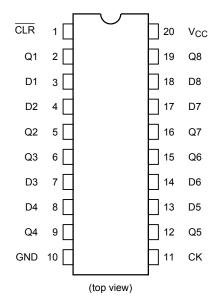
An input protection circuit ensures that 0 to 5.5 V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5 V to 3 V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

Features

- High speed: $f_{max} = 165 \text{ MHz}$ (typ.) at VCC = 5 V
- Low power dissipation: $I_{CC} = 4 \mu A \pmod{at Ta} = 25 \circ C$
- High noise immunity: V_{NIH} = V_{NIL} = 28% V_{CC} (min)
- Power down protection is provided on all inputs.
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: V_{CC} (opr) = 2 to 5.5 V
- Low noise: VOLP = 0.9 V (max)
- Pin and function compatible with 74ALS273



Pin Assignment



IEC Logic Symbol

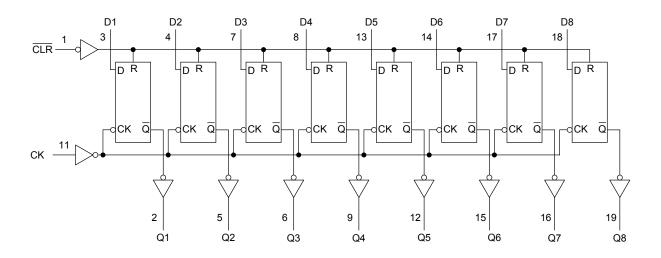
CLR (1) CK (11) D1 (3) D2 (4) D3 (7) D4 (8) D5 (13) D6 (14) D7 (17)	R >C1 1D	(2) (5) Q2 (6) Q3 (9) Q4 (12) Q5 (15) Q6 (16) Q7
D7 <u>(17)</u> D8 <u>(18)</u>		<u>(16)</u> Q7 <u>(19)</u> Q8

Truth Table

	Inputs		Output	Function
CLR	D	СК	Q	Function
L	Х	Х	L	Clear
Н	L		L	_
Н	Н		Н	_
Н	Х		Qn	No Change

X: Don't care

System Diagram



Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	–0.5 to 7.0	V
DC input voltage	V _{IN}	-0.5 to 7.0	V
DC output voltage	V _{OUT}	-0.5 to V _{CC} + 0.5	V
Input diode current	I _{IK}	-20	mA
Output diode current	I _{ок}	±20	mA
DC output current	IOUT	±25	mA
DC V _{CC} /ground current	ICC	±75	mA
Power dissipation	PD	180	mW
Storage temperature	T _{stg}	–65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V _{CC}	2.0 to 5.5	V
Input voltage	V _{IN}	0 to 5.5	V
Output voltage	V _{OUT}	0 to V _{CC}	V
Operating temperature	T _{opr}	-40 to 85	°C
Input rise and fall time	dt/dv	0 to 100 (V_{CC} = 3.3 \pm 0.3 V)	ns/V
	uvuv	0 to 20 (V_{CC} = 5 \pm 0.5 V)	115/ V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Electrical Characteristics

DC Characteristics

Characteristics	Symbol		Test Condition		٦	Γa = 25°0	0	-	a = 0 85°C	Unit
	,				Min	Тур.	Max	Min	Max	
High-level input voltage	V _{IH}		_		1.50 V _{CC} ×		_	1.50 V _{CC} ×		v
				5.5	0.7			0.7		
Low-level input				2.0	_	_	0.50	_	0.50	
voltage	V _{IL}		—	3.0 to 5.5			V _{CC} × 0.3		$V_{CC} \times 0.3$	V
				2.0	1.9	2.0	_	1.9		
		V _{IN} = V _{IH} or V _{IL}	$I_{OH}=-50~\mu A$	3.0	2.9	3.0	—	2.9	—	
High-level output voltage	V _{OH}			4.5	4.4	4.5	—	4.4	—	V
Ũ			$I_{OH} = -4 \text{ mA}$	3.0	2.58	_	_	2.48	_	
			$I_{OH} = -8 \text{ mA}$	4.5	3.94	—	—	3.80	—	
				2.0	_	0.0	0.1	_	0.1	
			$I_{OL}=50~\mu A$	3.0	—	0.0	0.1	—	0.1	
Low-level output voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL}		4.5	_	0.0	0.1	_	0.1	V
Ũ		2	$I_{OL} = 4 \text{ mA}$	3.0			0.36		0.44	
			$I_{OL} = 8 \text{ mA}$	4.5	—	—	0.36	—	0.44	
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5	_		±0.1		±1.0	μA
Quiescent supply current	ICC	V _{IN} = V _{CC} or	GND	5.5	_		4.0		40.0	μA

Timing Requirements (input: $t_r = t_f = 3$ ns)

Characteristics	Symbol Test Condition			Ta = 25°C		Ta = -40 to 85°C	Unit
			V _{CC} (V)	Тур.	Limit	Limit	
Minimum pulse width (CK)	t _{w (L)}		3.3 ± 0.3	_	5.5	6.5	20
Minimum pulse width (CK)	t _{w (H)}	—	5.0 ± 0.5	_	5.0	5.0	ns
Minimum pulse width (\overline{CLR})	t _{w (L)}	—	3.3 ± 0.3	_	5.0	6.0	ns
			5.0 ± 0.5	_	5.0	5.0	
	ts		3.3 ± 0.3	_	5.5	6.5	
Minimum set-up time		—	5.0 ± 0.5	—	4.5	4.5	ns
	t _h	_	$\textbf{3.3}\pm\textbf{0.3}$	_	1.0	1.0	
Minimum hold time			5.0 ± 0.5	—	1.0	1.0	ns
		_	3.3 ± 0.3	_	2.5	2.5	
Minimum removal time (CLR)	t _{rem}		5.0 ± 0.5	_	2.0	2.0	ns

AC Characteristics (input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol		st Condition	t Condition		Ta = 25°C			Ta = −40 to 85°C	
	,		V _{CC} (V)	C _L (pF)	Min	Тур.	Max	Min	Max	
			3.3 ± 0.3	15	_	8.7	13.6	1.0	16.0	
Propagation delay time	t _{pLH}		5.5 ± 0.5	50	_	11.2	17.1	1.0	19.5	ns
(CK-Q)	t _{pHL}		5.0 ± 0.5	15	_	5.8	9.0	1.0	10.5	115
. ,			5.0 ± 0.5	50	_	7.3	11.0	1.0	12.5	
			3.3 ± 0.3	15	_	8.9	13.6	1.0	16.0	
Propagation delay time	t		5.5 ± 0.5	50	_	11.4	17.1	1.0	19.5	ns
(CLR -Q)	t _{pHL} —		5.0 ± 0.5	15	_	5.2	8.5	1.0	10.0	_
、				50	_	6.7	10.5	1.0	12.0	
			3.3 ± 0.3	15	75	120	_	65	_	
Maximum clock	f _{max}		5.5 ± 0.5	50	50	75	_	45	_	MHz
frequency	Imax		5.0 ± 0.5	15	120	165	_	100	_	
			5.0 ± 0.5	50	80	110	_	70	_	
Output to output skew	t _{osLH}	(Note 1)	$\textbf{3.3}\pm\textbf{0.3}$	50	_	_	1.5	_	1.5	ns
tosHL	(NOLE T)	5.0 ± 0.5	50	_	_	1.0	_	1.0	115	
Input capacitance	C _{IN}		_		_	4	10		10	pF
Power dissipation capacitance	C _{PD}			(Note 2)		31		_	_	pF

Note 1: Parameter guaranteed by design.

 $t_{\text{OSLH}} = |t_{\text{pLHm}} - t_{\text{pLHn}}|, t_{\text{OSHL}} = |t_{\text{pHLm}} - t_{\text{pHLn}}|$

Note 2: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8$ (per bit)

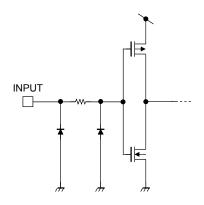
And the total C_{PD} when n pcs.of flip flop operate can be gained by the following equation:

 C_{PD} (total) = 22 + 9·n

Noise Characteristics (input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol	Test Condition	Τa		25°C	Unit
	Symbol		V _{CC} (V)	Тур.	Max	Offic
Quiet output maximum dynamic V_{OL}	V _{OLP}	$C_L = 50 \text{ pF}$	5.0	0.5	0.8	V
Quiet output minimum dynamic V_{OL}	V _{OLV}	$C_L = 50 \text{ pF}$	5.0	-0.5	-0.8	V
Minimum high level dynamic input voltage	V _{IHD}	$C_L = 50 \text{ pF}$	5.0	_	3.5	V
Maximum low level dynamic input voltage	V _{ILD}	C _L = 50 pF	5.0	_	1.5	V

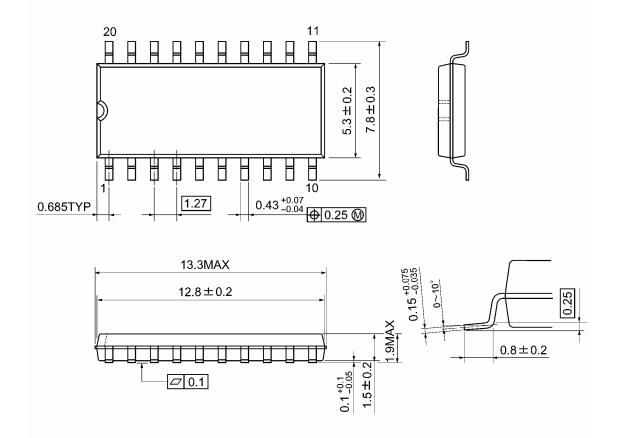
Input Equivalent Circuit



Package Dimensions

SOP20-P-300-1.27A

Unit: mm

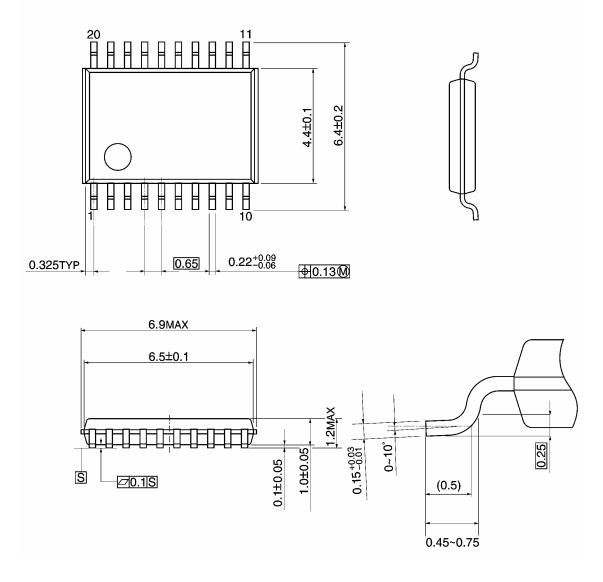


Weight: 0.22 g (typ.)

Package Dimensions

TSSOP20-P-0044-0.65A

Unit: mm



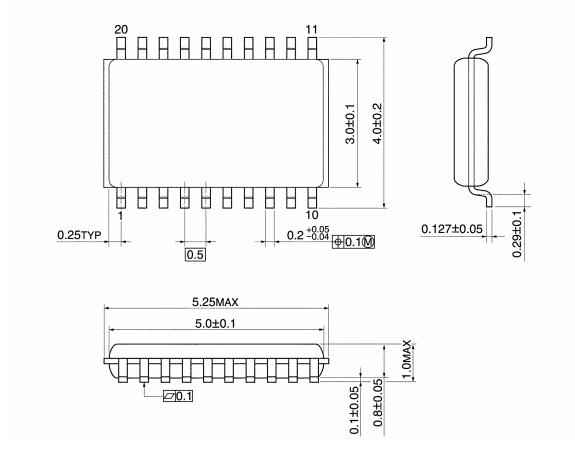
Weight: 0.08 g (typ.)

TOSHIBA

Package Dimensions

VSSOP20-P-0030-0.50

Unit: mm



Weight: 0.03 g (typ.)

9

RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
 In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any patents or other rights of TOSHIBA or the third parties.
- Please contact your sales representative for product-by-product details in this document regarding RoHS compatibility. Please use these products in this document in compliance with all applicable laws and regulations that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses occurring as a result of noncompliance with applicable laws and regulations.